

Notice of References Cited	Application/Control No. 10/066,326	Applicant(s)/Patent Under Reexamination TEIG ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6430729	08-2002	Dewey et al.	716/4
	B	US-US2003/0065535A1	04-2003	Karlov et al.	705/2
	C	US-6581195	06-2003	Tanaka	716/5
	D	US-6587997	07-2003	Chen et al.	716/4
	E	US-6549854	04-2003	Malinverno et al.	702/16
	F	US-6381555	04-2002	Sewell	702/181
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	W. A. Wright, "BAYESIAN APPROACH TO NEURAL-NETWORK MODELING WITH INPUT UNCERTAINTY," IEEE, NOV. 1999, PP. 1261-1270.
	V	Li et al., "MONTE CARLO SIMULATION TECHNIQUES FOR PROBABILISTIC TRACKING," IEEE, 2001, PP. 75-82.
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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